

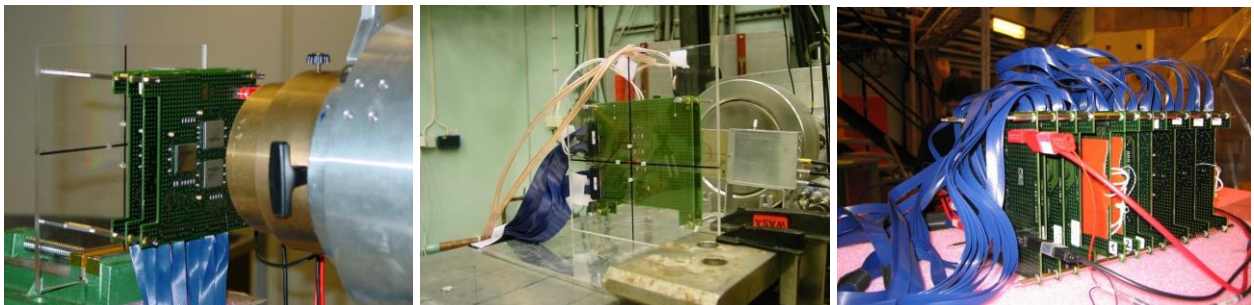
Radiation testing

As Soft Error threat increases in latest technology process nodes (65nm and below), various industries are in need to investigate this serious reliability issue. IROC, a world expert in the field, has developed in the past 10 years solutions for the analysis and test of radiation based Soft Error issues.

Complementary to our simulation platform, IROC Technologies accelerated test services provide the semiconductor industry with a fast and accurate method of SER assessment and test for any digital device. We measure the FIT (failure in time) rate of standalone components as well as whole systems using accelerated particles sources (Fast neutrons (cosmic rays), thermal neutrons, heavy ions, alpha particles, protons) for soft error or total ionizing dose sensitivity.

OVERVIEW

- Full compatibility to JEDEC JESD standards and MIL/ESA methods
- Turn key solution for whole systems to components
- Accelerated tests simulate in a few minutes the radiation impact of a lifetime in the field
- Expertise in monitoring accelerated particle facilities environment
- Flexible and dedicated hardware and powerful datalogs analysis tools
- Schedule reduces your time to market (shuttle program)
- Expertise and consulting on your test needs, operations and results
- Tests only at qualified facilities for the best service quality.
- Flexible schedule



PROCESS for TURN KEY SERVICE

1. Send device datasheet and sample availability date
2. iRoC delivers test plan, designs and manufactures daughterboards, develops test programs. Units must be delivered to iRoC 4 weeks prior to lab time (see schedule below).
3. Lab time takes 1 to 2 weeks
4. Analysis takes up to 4 weeks depending on quantity and quality of collected data. iRoC delivers preliminary test report
5. Once preliminary report is issued, customers have 4 weeks to provide feedbacks. Once approved, final report is released

2014-2015 TEST SHUTTLE SCHEDULE

